

FALL 2019 COLLOQUIUM SPEAKER

Breaking Down Research Barriers with In Situ TEM

New innovations are transforming the Transmission Electron Microscope (TEM) from a simple high-resolution image acquisition tool into a nanoscale materials research and development laboratory. Researchers can now better understand material behavior by analyzing samples in real-world gas or liquid environments, at high temperature and with ultra-low noise electrochemical and electrical characterization techniques. As a leader in in situ TEM technology, Protochips seeks to grow adoption into these techniques by addressing fundamental barriers to entry that tend to prevent potential researchers from taking advantage of the opportunity to observe and analyze their samples in the environments in which they truly exist or are meant to perform. Expansion of this community relies upon a real paradigm shift in the perceived amount of difficulty, along with a simultaneous increase in the level of performance to be expected in these experiments. Our very newest product release delivers both of these promises in a stunning step forward. In this presentation, we show both some of the most recent in situ results and findings from leading researchers as well as new product launches that completely redefine the experience of conducting meaningful TEM experiments in any lab.

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WINSTON CHUNG HALL 205/206

1 PM - 2 PM



Jordan Moering

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Jordan Completed his Ph.D in Material Science and Engineering where his research focused on utilizing EBSD, FIB, SEM, and TEM to characterize the deformation mechanics of nanocrystalline metals. He joined Protochips in 2016 where he works with the Sales and product development team to explore new and expanding opportunities for in situ tools and solutions. In a previous life, Jordan was an entrepreneur and technology development consultant, evaluating new technologies for commercialization while running a startup company specializing in the photonics market.